



SDI Review Form 1.6

Journal Name:	International Research Journal of Pure and Applied Chemistry
Manuscript Number:	Ms_IRJPAC_20775
Title of the Manuscript:	Preparation of ternary (Ni ₃ Pb ₂ S ₂) thin films by chemical bath deposition method
Type of the Article	

General guideline for Peer Review process:

This journal's peer review policy states that **NO** manuscript should be rejected only on the basis of '**lack of Novelty**', provided the manuscript is scientifically robust and technically sound.

To know the complete guideline for Peer Review process, reviewers are requested to visit this link:

(<http://www.sciencedomain.org/page.php?id=sdi-general-editorial-policy#Peer-Review-Guideline>)

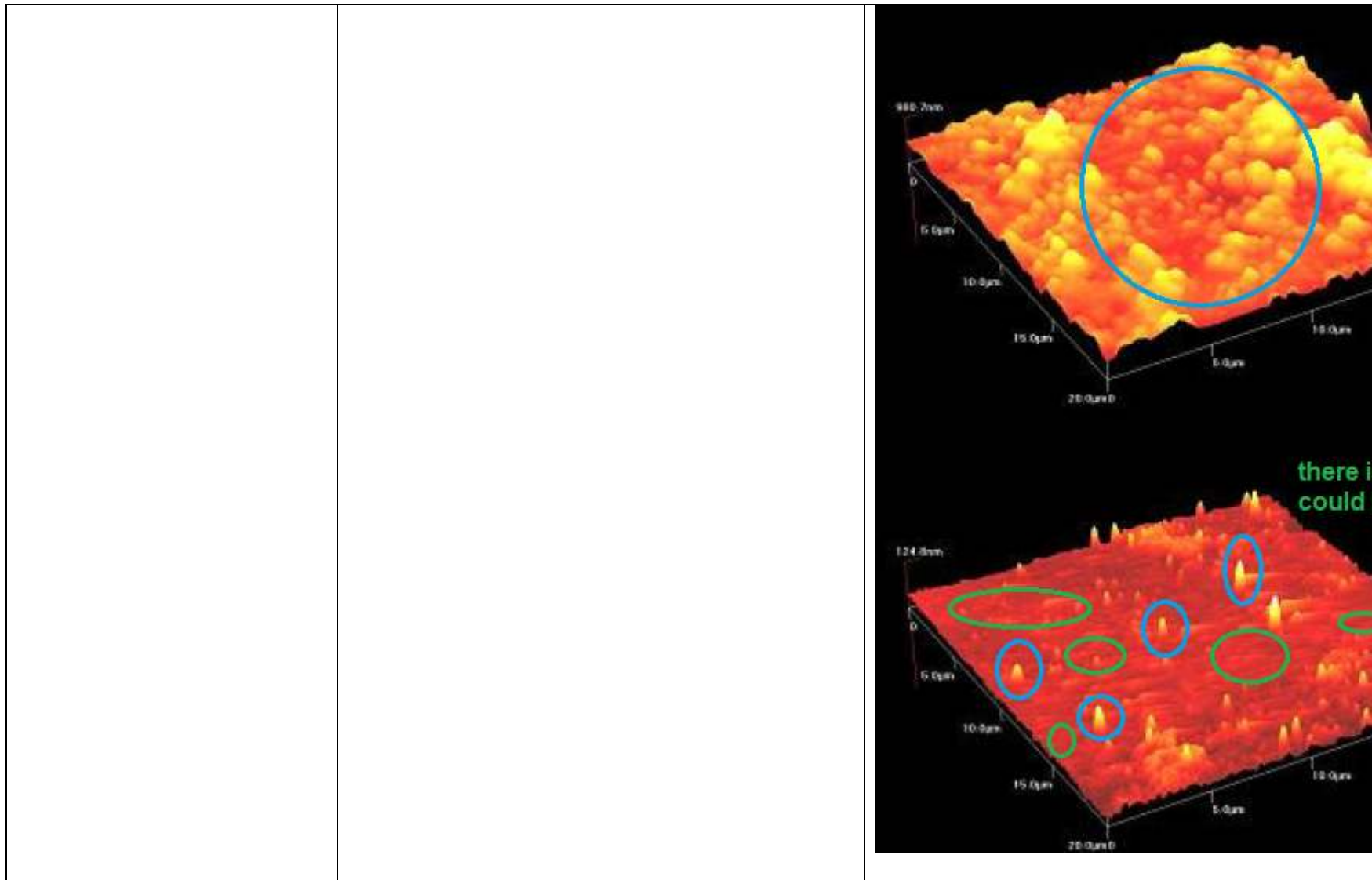


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PART 1: Review Comments

	Reviewer's comment	Author's comment (if agreed with reviewer, correct the manuscript and highlight that part in the manuscript. It is mandatory that authors should write his/her feedback here)
Compulsory REVISION comments	1) The authors wrote "without complexing agent" and "in the absence of complexing agent". Could you please explain the meaning of this description, for the readers in the fields different from the author's one. 2) Figure 1 might include very interesting information, because of the existence of "several small grains" and "a few bigger grains". However, the reader cannot identify which is the small grains or bigger grains. Similar to the comment 1), the readers in the different field cannot recognize what and how the valuable results were. The expression "the incomplete surface coverage" and "randomly distributed " are similarly not easily recognized from Figure 1. Could you please describe what happened, by sentences. 3) Could you please give the film thickness value. Any values, average, maximum or minimum, are welcome.	[1] I have changed them to "in the absence of complexing agent". To avoid any confused. [2] If you are material science researcher, you should know how to interpret atomic force microscope images. He/she should know how to recognize the grain size from AFM. How to interpret incomplete surface coverage and randomly distributed. Here, I can show you some examples of AFM images from other researchers. I hope that you as a reviewer can understand this interpretation.

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		I think, readers can easily to recognise these images if I present more results. [3] Meanwhile, the thickness of the films was 929.6 nm
<u>Minor</u> REVISION comments		
<u>Optional/General</u> comments		